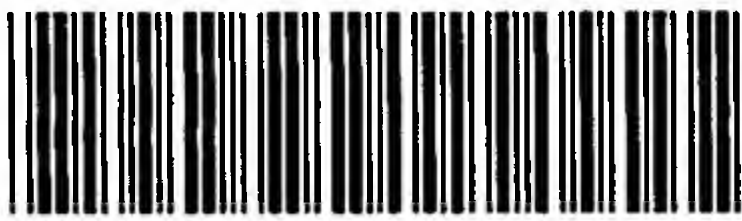


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/709,824	SHIUNG, DAVID	
	Examiner	Art Unit	
	Tan V. Mai	2193	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Double Patent Check NEW Data Bases Search (see search history printout(s))	11/26/2007	MAI